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# RADIATION TEST REPORT FOR ADP3300 (COMMERCIAL DEVICES)

# PROJECT STEREO

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**Radiation Test Report** 

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# TABLE OF CONTENTS

1	INT	RODUCTION	.5
		PLICABLE DOCUMENTS	
		ST DESCRIPTION	
		Measurement set-up	
		Thermal conditions	
		Dosimetry	
		Test Results	



Test Report Number	
Project	STEREO
SCC Component no.	
Component Designation	50 mA Low Dropout Linear Regulator
Irradiation Spec. no.	garante garant
Family	Integrated Circuits
Group	Silicon Monolithic
Package	Plastic DIP/SO
Component Specification	
Test House Name	ESA / ESTEC
Irradiation Test Plan Number	
Manufacturer name	
Application type of Acceptance	
Serial Number of samples	Five (5) samples serialised as Ref, 1, 2, 3 and 4
Manufacturing Date Code	(-)
Irradiation Measurement Interval:	
Biased	Yes
Unbiased:	No
Circuit Reference:	
Supply Voltage:	+8V
Temp °C:	Room temperature $20 \pm 3$
Duration:	•
Electrical Measurement	
Parameters	
Facility	
Source:	60Co
Energy:	
Dose Rate:	4.6 rad/min
Absorbed Material:	N/A
Thickness:	N/A
Temperature °C:	$20 \pm 3$
Dosimetry / Calibration method.	A calibrated NE2571, 0.66cc air ionisation chamber read by a calibrated
	Farmer 2670 dosimeter.
Anneal Test	
Biased	Yes
Unbiased	No
Bias Circuit Reference	
Supply Voltage	+8V
Duration	24 hours room temperature and 336 hours at +80 °C



#### 1 INTRODUCTION

The following document contains the TID Radiation Test Report for ADP3300 CMOS analog multiplexer for the STEREO project.

#### 2 APPLICABLE DOCUMENTS

AD1- ESA/SCC 22900 "Total Dose Steady-State Irradiation Test Method"

#### 3 TEST DESCRIPTION

Five (5) ADP3300, Flight Lot, AD devices were selected for TID irradiation testing at the ESTEC <sup>60</sup>Co facility. Irradiations were performed at a dose rate of 4.6 rad(Si)/min. Post irradiation annealing measurements were also performed on the devices.

Of the selected devices, one was assigned as a reference device while, four were serialised for radiation exposure. All devices were of the Small Outline (SO) type and for ease of measurements were soldered on special adapter boards. These boards were mounted on the irradiation test-boards during exposure. After each exposure-step the adapter boards were removed and mounted on the SZ-test system for parametric measurements. The irradiation test-board can accommodate and bias four adapter boards (four devices). Each op-amp was operated in a high gain configuration for real-time measurement of the output-offset voltage. The biasing scheme of the operational amplifiers is illustrated in figure 1. The operating conditions during irradiation were provided by the STEREO project. The device operating conditions, temperature conditions and applied dose rates are listed in table 1.

Figure 1 Schematic diagram of irradiation biasing scheme.



Parameter	Ref. Dev.	Dev1	Dev2	Dev3	Dev4
Bias During	NA	+8V	+8V	+8V	+8V
Irradiation					
Dose Rate	NA	4.6rad(Si)/min	4.6rad(Si)/min	4.6rad(Si)/min	4.6rad(Si)/min
Irradiation	$20 \pm 3$ °C	$20 \pm 3$ °C	$20 \pm 3$ °C	$20 \pm 3$ °C	$20 \pm 3  {}^{\circ}\text{C}$
Temperature					

**Table 1 Irradiation Test Conditions** 

# 3.1 Measurement set-up

Two sets of measurements were performed one set of continuous measurements (in 10 min intervals) during the irradiation runs and one set of parametric measurement at regular intervals between irradiation steps. Continuous measurements were performed employing a HP-VEE system consisting of:

- HP 6626A System DC Power Supply
- HP 34970A Data Acquisition / Switch Unit

Measurement number	Devices 1,2,3 and 4	
1		
2		

Table 2 Continuous measurements for each device during irradiation.

Parametric measurements were performed employing a SZ parametric tests system:

- SZ M3000 Test Station Sm02B
- M3000 TA10 Test Adapter
- Software UTS-Version 2.3.3

Table 3 list all parametric measurements performed and their limit values.



Test Parameter	Limit
Output Voltage	Lower 4.96V, Upper 5.04V
Output Voltage at	Lower 4.96V, Upper 5.04V
5mA	
Line Regulation	Lower –1mV, Upper 1mV
Load Regulation	Lower –10mV,
	Upper 10mV
Dropout ay 1mA	Upper 30mV
Dropout at 10mA	Upper 70mV
Dropout at 50mA	Upper 170mV
Ground Current 1mA	Upper 0.3mA
Ground Current	Upper 1.7mA
50mA	
Ground Current	Upper 1.2mA
dropout	

Table 3 Parameters measured by the SZ parametric Test System

The time between irradiation stop, performing parametric measurements and starting irradiation for all irradiation steps were less than 60min. 4 irradiation steps were performed and parametric measurements performed after each step (parametric also performed for the reference device. Pre-irradiation measurements were performed on all devices. Table 4 illustrates the irradiation and measurement history.

Irradiation steps	Ref.	Dev1	Dev2	Dev3	Dev4
	Dev.				
Pre-rad. Par.	Yes	Yes	Yes	Yes	Yes
measurements					
5.2 krad(water)					
par. measurements	Yes	Yes	Yes	Yes	Yes
7.4 krad(water)					
par. measurements	Yes	Yes	Yes	Yes	Yes
12.3 krad(water)					
Par. Measurements	Yes	Yes	Yes	Yes	Yes
14.6 krad(water)					
Par Measurements	Yes	Yes	Yes	Yes	Yes
19.6 Krad(water)					
Par Measurements	Yes	Yes	Yes	Yes	Yes
43 Krad(water)					
Par Measurements	Yes	Yes	Yes	Yes	Yes

**Table 4 Irradiation and measurement history** 



## 3.2 Thermal conditions

All irradiations and measurements were performed at room temperature ( $20 \pm 3$  °C).

# 3.3 Dosimetry

A calibrated NE2571, 0.66cc air ionisation chamber read by a calibrated Farmer 2670 dosimeter was used to measure the Total Ionising Dose.

## 3.4 Test Results

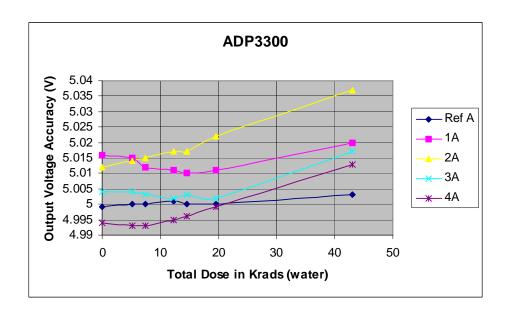


Figure 2 Output Voltage Accuracy as a function of Dose, gamma 5.2 rad(water)/min



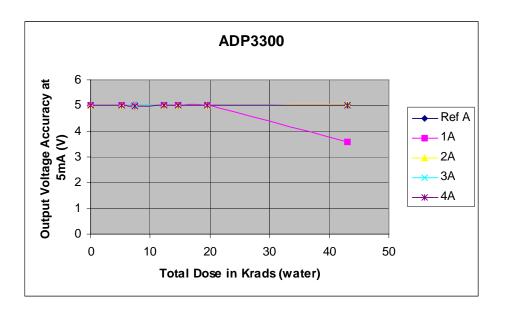


Figure 3 Output Voltage at 5mA as a function of dose, gamma 5.2 rad(water)/min

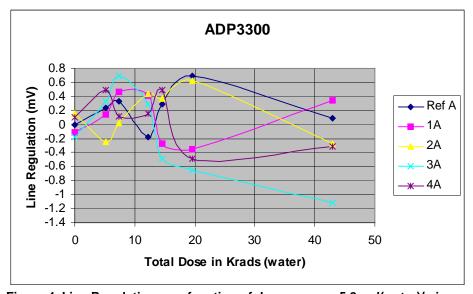


Figure 4 Line Regulation as a function of dose, gamma 5.2 rad(water)/min



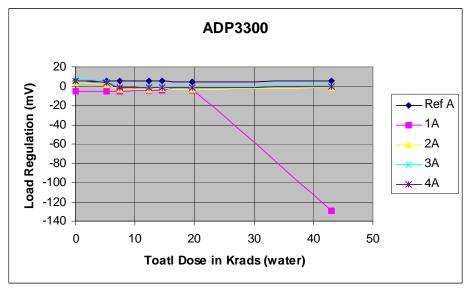


Figure 5 Load Regulation as a function of dose, gamma 5.2 rad(water)/min

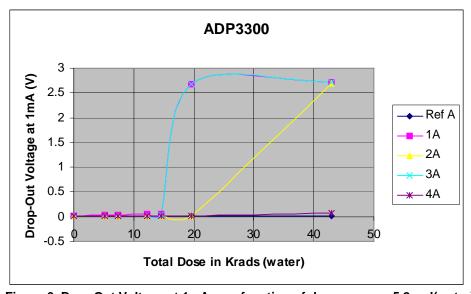


Figure 6 Drop Out Voltage at 1mA as a function of dose, gamma 5.2 rad(water)/min



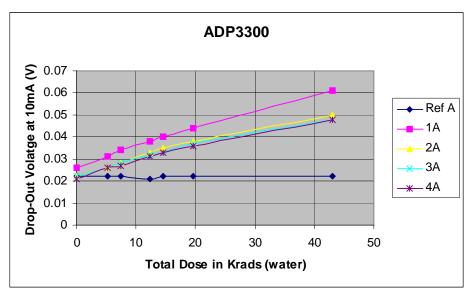


Figure 7 Drop Out Voltage at 10mA as a function of dose, gamma 5.2 rad(water)/min

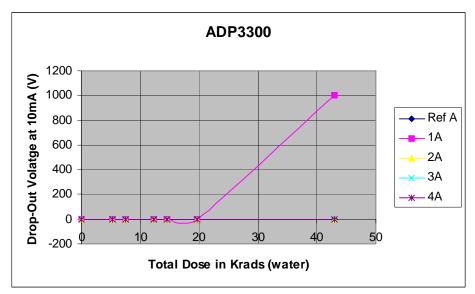


Figure 8 Drop Out Volatge at 50mA as a function of dose, gamma 5.2 rad(water)/min



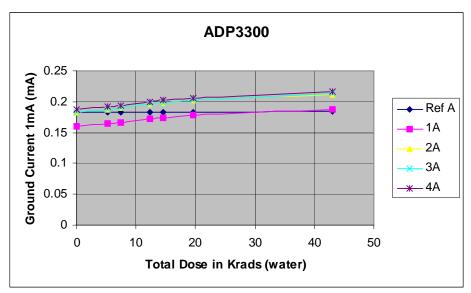


Figure 9 Ground Current at 1mA as a function of dose, gamma 5.2 rad(water)/min

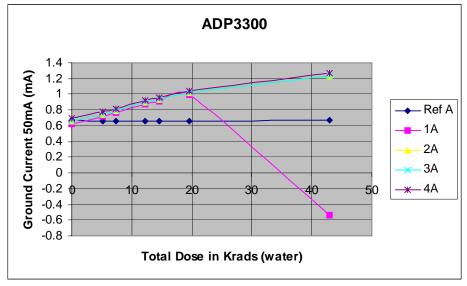


Figure 10 Ground Current at 50mA as a function of dose, gamma 5.2 rad(water)/min



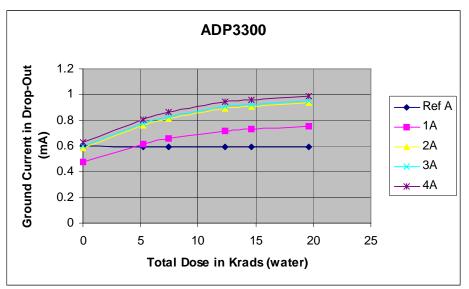


Figure 11 Ground Current in drop-out as a function of dose, gamma 5.2 rad(water)/min